



PTO/SB/088 (10-96) [reproduced]
Approved for use through 10/31/99. CMB 0651-0031
Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Substitute for Form 1449B/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete If Known

Application Number	10/695,019
Filing Date	October 29, 2003
First Named Inventor	Douglas S. McGregor, et al.
Group Art Unit	2828 2884
Examiner Name	
Attorney Docket Number	UOM 0316 PUSP

Sheet 1 of 1

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
(G)		MCGREGOR, DOULGAS S., ET AL., Bulk GaAs-Based Neutron Detectors For Spent Fuel Analysis, Proceedings of ICONE 8, 8 th Int'l Conf. on Nuclear Eng., Baltimore, MD, April 2-6, 2000, pp. 1-5	
(G)		DE LURGIO, PATRICK M., ET AL., A Neutron Detector To Monitor The Intensity of Transmitted Neutrons For Small-Angle Neutron Scattering Instruments, Elsevier Science B.V., Nuclear Instruments And Methods in Physics Research A 505, 2003, pp. 46-49	
(G)		KLANN, RAYMOND T., ET AL., Development of Semiconductor Detectors For Fast Neutron Radiography, 15 th Int'l. conf. on Applications of Accelerators in Research and Industry, November 2000, pp. 1-4	
(G)		GERSCH, H.K., ET AL., The Effect of Incremental Gamma-Ray Doses and Incremental Neutron Fluences Upon The Performance of Self-Biased ¹⁰ B-Coated High-Purity Epitaxial GaAs Thermal Neutron Detectors, Nuclear Instruments and Methods in Physics Research A 489, February 12, 2002, pp. 85-98	
(G)		MCGREGOR, DOUGLAS S., ET AL., Thin-Film-Coated Detectors For Neutron Detectors, J. of Korean Asso. For Radiation Protection, Vol. 26, 2001, pp. 167-175	
(G)		MCGREGOR, DOUGLAS, S., ET AL., Designs For Thin-Film-Coated Semiconductor Thermal Neutron Detectors, University of Michigan, Ann Arbor, Michigan, November 14, 2001, pp. 1-6	
(G)		MCGREGOR, DOULGAS S., ET AL., Recent Results From Thin-Film-Coated Semiconductor Neutron Detectors, Proceedings of SPIE, Vol. 4784, 2002, pp. 164-182	

Examiner
Signature

Date
Considered

26 July 05

¹EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.
²Unique citation designation number. ³Applicant is to place a check mark here if English language Translation is attached.

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

APR 02 2004

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Complete if Known

Application Number	10/695,019
Filing Date	October 29, 2003
First Named Inventor	Douglas S. McGregor, et al.
Group Art Unit	2878 2884
Examiner Name	
Attorney Docket Number	UOM 0316 PUSP

Sheet

1

of

4

Attorney Docket Number

UOM 0316 PUSP

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

**Examiner
Signature**

Date
Considered

07 July 05

Examiner Signature	Considered	Not Considered
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		

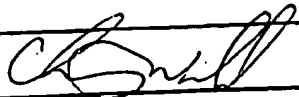
1 Unique citation designation number. * See attached Kinds of U.S. Patent Documents. * Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). * For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. * Indicate, as indicated on the document under WIPO Standard ST. 16 if possible. * Applicant is to place a check mark here

* Kind of document by the appropriate symbol
if English language Translation is attached.

Substitute for Form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)			Complete If Known		
			Application Number	10/695,019	
			Filing Date	October 29, 2003	
			First Named Inventor	Douglas S. McGregor, et al.	
			Group Art Unit	2878 2874	
			Examiner Name		
Sheet	2	of	4	Attorney Docket Number	UOM 0316 PUSP

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

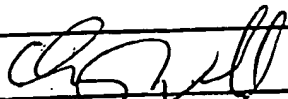
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CG		MCGREGOR, DOUGLAS S., ET AL., Semi-Insulating Bulk GaAs Thermal Neutron Imaging Arrays, IEEE Transactions on Nuclear Science, Vol. 43, No. 3, June 1996, pp. 1357-1364	
CG		ROSE, A., Sputtered Boron Films on Silicon Surface Barrier Detectors, Nuclear Instruments and Methods, 52, 1967, pp. 166-170	
CG		FEIGL B., ET AL., Der Gd-Neutronenzähler, Nuclear Instruments and Methods, 61, Wien, Austria, 1968, pp. 349-356	
CG		MIRESHGHI, A., ET AL., High Efficiency Neutron Sensitive Amorphous Silicon Pixel Detectors, IEEE Transactions on Nuclear Science, Vol. 41, No. 4, August 1994, pp. 915-921	
CG		FOULON, F., ET AL., Neutron Detectors Made From Chemically Vapour Deposited Semiconductors, Proc. MRS, 487, 1998, pp. 591-596	
CG		DULLOO, A.R., ET AL., Radiation Response Testing of Silicon Carbide Semiconductor Neutron Detectors For Monitoring Thermal Neutron Flux, Report 97-9TK1-NUSIC-R1, Westinghouse STC, Pittsburgh, PA, November 18, 1997, pp. 6-1 - 6-14	
CG		KNOLL, GLENN F., Radiation Detection and Measurement, 3 rd Ed. John Wiley & Sons, Inc., New York, 2000, Chapter 14, pp. 505-508	
CG		GARBER, D.I., ET AL., Neutron Cross Sections, 3 rd Edition, Vol. 11, Curves, Brookhaven National Laboratory, Upton, January 1976, pp. 11-13 & pp. 23-24	
CG		MCLANE, VICTORIA, ET AL., Neutron Cross Sections, Vol. 2, Neutron Cross Section Curves, Academic Press, San Diego, CA, 1988, pp. 12-13 & pp. 26-27	
CG		MCGREGOR, DOUGLAS, S., ET AL., Thin-Film-Coated Bulk GaAs Detectors for Thermal and Fast Neutron Measurements, Nuclear Instruments and Methods in Physics Research A 466, 2001, pp. 126-141	
CG		MCGREGOR, DOUGLAS, S., ET AL., Design Considerations for Thin Film Coated Semiconductor Thermal Neutron Detectors -- I: Basics Regarding Alpha Particle Emitting Neutron Reactive Films, Nuclear Instruments & Methods, A 500, 2003, pp. 272-308	

Examiner Signature		Date Considered	26 July 05
-----------------------	---	--------------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

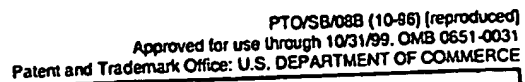
¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.

Substitute for Form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known	
				Application Number	10/695,019
				Filing Date	October 29, 2003
				First Named Inventor	Douglas S. McGregor, et al.
				Group Art Unit	2828 2884
Examiner Name					
Sheet	3	of	4	Attorney Docket Number	UOM 0316 PUSP
OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
(G)		PUCKETT, P.R., ET AL., Thin Film Processes II, Chapter V-2, J.L. Vossen and W. Kern, Eds., Academic Press, Boston, 1991, pp. 749			
(G)		SZE, S.M., VLSI Technology, McGraw-Hill, New York, 1983			
(G)		RUSKA, W.S., Microelectronic Processing, McGraw-Hill, New York, 1987			
(G)		WOLF, STANLEY, ET AL., Silicon Processing for the VLSI Era, Lattice Press, Sunset Beach, 1986			
(G)		MCGREGOR, DOUGLAS, S., ET AL., Self-Biased Boron-10 Coated High-Purity Epitaxial GaAs Thermal Neutron Detectors, IEEE Transactions on Nuclear Science, Vol. 47, No. 4, August 2000, pp. 1364-1370			
(G)		KLANN RAYMOND T., ET AL., Development of Coated Gallium Arsenide Neutron Detectors, Conference Record of ICONE-8, 8 th International Conf. on Nuclear Eng., April 2-6, 2000, Baltimore, MD, pp. 1-6			
(G)		MCGREGOR, DOUGLAS, S., ET AL., New Surface Morphology for Low Stress Thin-Film-Coated Thermal Neutron Detectors, IEEE Transactions on Nuclear Science, Vol. 49, No. 4, August 2002, pp. 1999-2004			
		http://www.mems-exchange.org/			
		http://physics.nist.gov/Ma/ResPro/1/rfcell/drawings.html			
(G)		SCHELLEN, J., ET AL., A New Neutron Detector Development Based on Silicon Semiconductor and LiF Converter, Physica B 234-236, 1997, pp. 1084-1086			
(G)		ATOMNAYA ENERGIYA, Soviet Atomic energy, Russian Original, Vol. 62, No. 4, April 1987, pp. 316-319			

Examiner Signature		Date Considered	27 July 05
--------------------	---	-----------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.



INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Sheet	4	of	4
-------	---	----	---

Application Number	10/695,019
Filing Date	October 29, 2003
First Named Inventor	Douglas S. McGregor, et al.
Group Art Unit	2078 2-884
Examiner Name	
Attorney Docket Number	UOM 0316 PUSP

[illegible]

26 July 05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

*Unique citation designation number. *Applicant is to place a check mark here if English language Translation is attached.

egor

01PE

MAR 07 2015

PATENT & TRADEMARK OFFICE

[illegible][illegible]

Examiner Signature	<i>[Signature]</i>	Date Considered	27 July 05
-----------------------	--------------------	--------------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.